

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:	Mehrdad Nikoonahad et al.		
Title:	Optical System For Measuring Samples Using Short Wavelength Radiation		
Application No.:	10/718,126	Filing Date:	November 19, 2003
Examiner:	Pham, Hoa Q.	Group Art Unit:	2886
Docket No.:	TNCR.197US1	Conf. No.:	9108

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO FINAL OFFICE ACTION AND AMENDMENT

Sir:

This is in response to the final Office Action dated April 18, 2007, setting a shortened statutory period for response to expire July 18, 2007. A petition for an extension of time with accompanying fee is being filed herewith to extend the response period to September 18, 2007.

Claim Amendments are reflected in the listing of claims, which begins on page 2 of this paper.

Specification Amendments have not been made.

Drawing Amendments begin on page 34 of this paper.

Remarks begin on page 35 of this paper.

An Appendix including both replacement drawing sheet and an annotated drawing sheet showing changes is attached following page 42 of this paper.

Reconsideration is kindly requested in light of the following amendments and remarks.